

## **Description**

The HXY20N06DF uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

#### **General Features**

 $V_{DS} = 60V I_{D} = 15A$ 

 $R_{DS(ON)}$  < 40m $\Omega$  @  $V_{GS}$ =10V

### **Application**

**Battery protection** 

Load switch

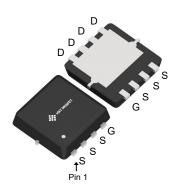
Uninterruptible power supply

## **Package Marking and Ordering Information**

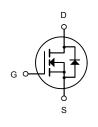
Product ID	Pack	Brand	Qty(PCS)
HXY20N06DF	DFN3X3-8L	HXY MOSFET	5000

## Absolute Maximum Ratings (T<sub>C</sub>=25°C unless otherwise noted)

Symbol	Parameter	Rating	Units
VDS	Drain-Source Voltage	60	V
Vgs	Gate-Source Voltage	±20	V
ID@TA=25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	15	А
ID@TA=70°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	11	А
Ірм	Pulsed Drain Current <sup>2</sup>	46	А
EAS	Single Pulse Avalanche Energy <sup>3</sup>	25.5	mJ
IAS	Avalanche Current	20	А
P <sub>D</sub> @T <sub>C</sub> =25°C	Total Power Dissipation <sup>4</sup>	34.7	W
Тѕтс	Storage Temperature Range	-55 to 175	°C
TJ	Operating Junction Temperature Range	-55 to 175	°C
$R_{ heta JA}$	Thermal Resistance Junction-Ambient <sup>1</sup>	62	°C/W



DFN3X3-8L



N-Channel MOSFET

# Electrical Characteristics (T<sub>J</sub>=25°C, unless otherwise noted)

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Units
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	60	-	-	V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS}$ =60V, $V_{GS}$ = 0V,	-	-	1.0	μΑ
I <sub>GSS</sub>	Gate to Body Leakage Current	$V_{DS}$ =0V, $V_{GS}$ = ±20V	-	-	±100	nA
$V_{GS(th)}$	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	1.0	1.6	2.5	V
D	Static Drain-Source on-Resistance	V <sub>GS</sub> =10V, I <sub>D</sub> =5A	-	28	40	mΩ
$R_{DS(on)}$		V <sub>GS</sub> =4.5V, I <sub>D</sub> =3A	-	36	50	
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> =25V, V <sub>GS</sub> =0V, f=1.0MHz	-	1148	-	pF
Coss	Output Capacitance		-	58.5	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		-	49.4	-	pF
Qg	Total Gate Charge	V <sub>DS</sub> =30V, I <sub>D</sub> =2.5A, V <sub>GS</sub> =10V	-	20.3	-	nC
Q <sub>gs</sub>	Gate-Source Charge		-	3.7	-	nC
$Q_{gd}$	Gate-Drain("Miller") Charge		-	5.3	-	nC
t <sub>d(on)</sub>	Turn-on Delay Time	$V_{DS}$ =30V, $I_{D}$ =5A, $R_{G}$ =1.8 $\Omega$ , $V_{GS}$ =10V	-	7.6	_	ns
t <sub>r</sub>	Turn-on Rise Time		-	20	-	ns
$t_{d(off)}$	Turn-off Delay Time		-	15	-	ns
t <sub>f</sub>	Turn-off Fall Time		-	24	-	ns
Is	Maximum Continuous Drain to Source Diode Forward Current		-	-	5	А
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current		-	-	15	Α
\ /	Drain to Source Diode Forward				4.0	V
$V_{SD}$	Voltage	$V_{GS}$ =0V, $I_{S}$ =5A	-	-	1.2	V
trr	Body Diode Reverse Recovery Time		-	29	-	ns
Orr	Body Diode Reverse Recovery	Reverse Recovery I <sub>F</sub> =5A, dI/dt=100A/µs		12		20
Qrr	Charge		_	43	-	nC

Notes:1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

- 2. EAS condition : T\_J=25°C,V\_DD=30V,V\_G=10V,L=0.5mH,Rg=25 $\Omega$ ,I\_AS=8.7A
- 3. Pulse Test: Pulse Width≤300µs, Duty Cycle≤0.5%

## **Typical Characteristics**

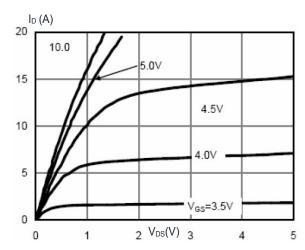


Figure1: Output Characteristics

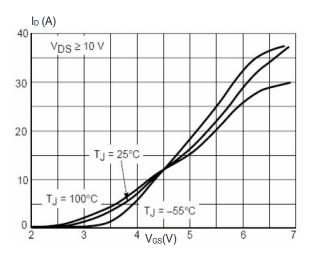


Figure 2: Typical Transfer Characteristics

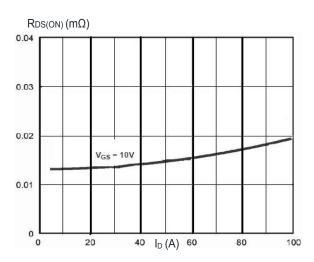
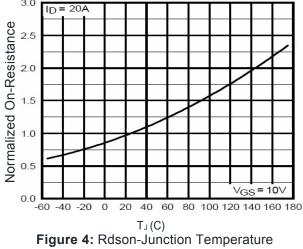


Figure 3: Rdson- Drain Current



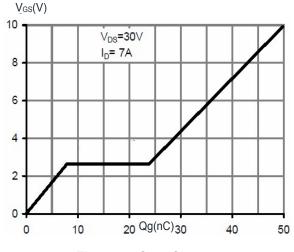


Figure 5: Gate Chare

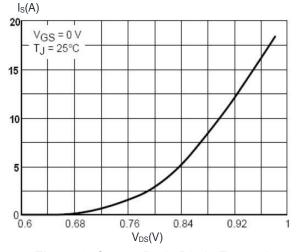


Figure 6: Source-Drain Diode Forward

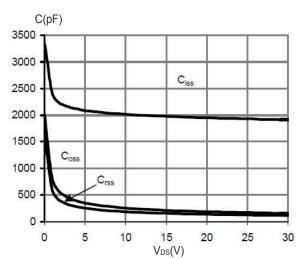


Figure 7: Capacitance vs Vds

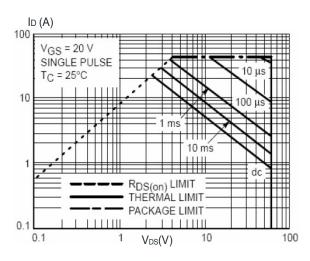


Figure 7: Safe Operation Area

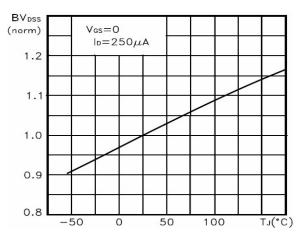


Figure 8: BVDSS vs Junction Temerature

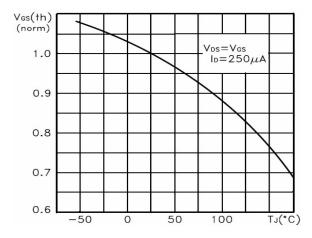


Figure 9: VGS(th) vs Junction Temperature

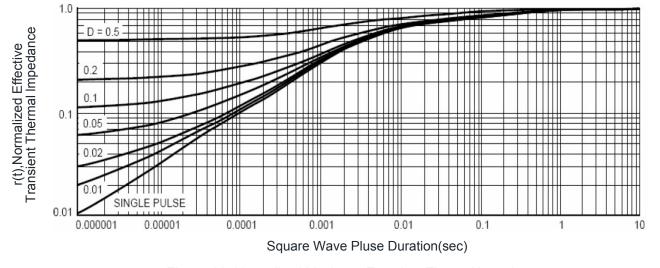


Figure 11: Normalized Maximum Transient Thermal Impedance

### **Test Circuit**

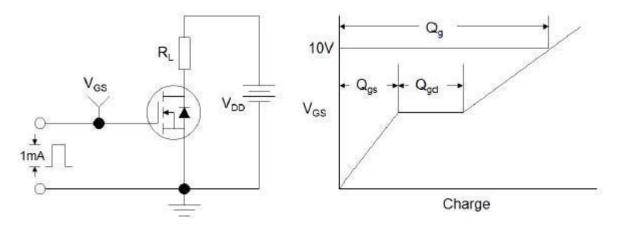


Figure1:Gate Charge Test Circuit & Waveform

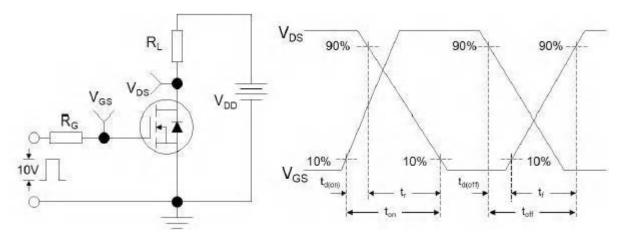


Figure 2: Resistive Switching Test Circuit & Waveforms

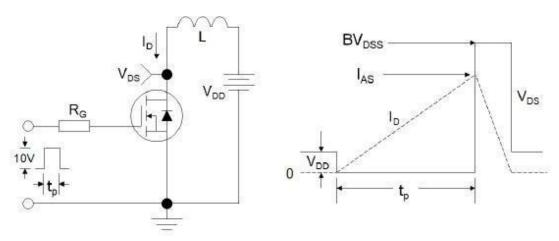
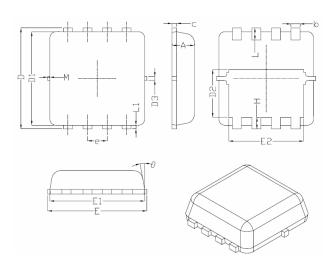


Figure 3:Unclamped Inductive Switching Test Circuit & Waveforms



# **DFN3X3-8L Package Information**



Comphal	Dimensions In Millimeters			
Symbol	Min.	Nom.	Max.	
A	0.70	0.75	0.80	
b	0.25	0.30	0.35	
С	0.10	0.15	0.25	
D	3.25	3.35	3.45	
D1	3.00	3.10	3.20	
D2	1.48	1.58	1.68	
D3	-	0.13	-	
E	3.20	3.30	3.40	
E1	3.00	3.15	3.20	
E2	2.39	2.49	2.59	
е	0.65BSC			
Н	0.30	0.39	0.50	
L	0.30	0.40	0.50	
L1	-	0.13	-	
M	*	*	0.15	
θ		10 <sup>°</sup>	12 <sup>°</sup>	



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